



Reliability and Fault Tolerance Techniques in Emerging Technologies

Guest Editors:

Prof. Dr. Matteo Sonza Reorda

Department of Control and
Computer Engineering,
Politecnico di Torino, 10129
Torino, Italy

Dr. Sarah Azimi

Department of Control and
Computer Engineering,
Politecnico di Torino, 10129
Torino, Italy

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Message from the Guest Editors

The focus of this Special Issue is on the advancements in reliability and fault tolerance techniques for emerging semiconductor technologies, including three-dimensional technologies (such as 2.5D/3D Integrated Circuits), nanoscale FinFET devices, innovative memories (such as PCRAM, STTMRAM, RRAM), introducing state-of-the-art investigations on the methods and techniques as well as modern implementation technologies enabling an effective and efficient development of highly reliable systems and designs.

The topics of interest include but are not limited to all the following topics applied to emerging semiconductor technologies:

- Design for Reliability
- Design for Single Event Effect Hardening
- Single Event Effect Modeling, Analysis, and Mitigation
- Modeling and Analysis of Radiation Effect
- Hardening Techniques for Transient Errors
- CAD Tools for 3D Technologies
- Design and Test for 2.5D/3D ICs
- Design and Test for 3D memories
- Design and Test for Emerging Memory Technologies





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Editor-in-Chief

Prof. Dr. Flavio Canavero

Department of Electronics and
Telecommunications,
Politecnico di Torino, 10129
Torino, Italy

Message from the Editor-in-Chief

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Electronics Editorial Office
MDPI, St. Alban-Anlage 66
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